

### Amendments to the Claims

1. (CURRENTLY AMENDED) A method for the self-testing of a reference voltage in electronic components, characterized in that the reference voltage ( $U_{ref}$ ) is the variable of a function  $f(U_{ref})$  that has an extreme at the point where the selected nominal value ( $U_{ref.test}$ ) of the reference voltage ( $U_{ref}$ ) is situated and in a self-test, the values of the function are determined in succession for the reference voltage ( $U_{ref}$ ) and for two further test voltages ( $U_{ref} + \Delta U_{ref}$ ;  $U_{ref} - \Delta U_{ref}$ ) that differ from the reference voltage ( $U_{ref}$ ) by only small positive and negative amounts ( $+\Delta U_{ref}$ ;  $-\Delta U_{ref}$ ) respectively and these values are compared with one another, and if the values of the function for the test voltages ( $U_{ref} + \Delta U_{ref}$ ;  $U_{ref} - \Delta U_{ref}$ ) differ from the value of the function for the reference voltage ( $U_{ref}$ ) in the same direction a pass signal is generated, or if not, a fail signal is generated.

2. (CURRENTLY AMENDED) A circuit arrangement for the self-testing of a reference voltage ( $U_{ref}$ ) in electronic components, characterized in that it comprises a function generator having a function  $f(U_{ref})$  that has an extreme at the point where the selected nominal value ( $U_{ref.test}$ ) of the reference voltage ( $U_{ref}$ ) is situated, and the input signals to which function generator are the reference voltage ( $U_{ref}$ ) and two further test voltages ( $U_{ref} + \Delta U_{ref}$ ;  $U_{ref} - \Delta U_{ref}$ ) that differ from the reference voltage ( $U_{ref}$ ) by only small positive and negative amounts respectively, and the output signals from which function generator are fed to sample & hold circuits, and in that it comprises two comparator circuits for comparing the values of the function for the reference voltage ( $U_{ref}$ ) and for respective test voltages ( $U_{ref} + \Delta U_{ref}$ ;  $U_{ref} - \Delta U_{ref}$ ), the outputs of which comparator circuits generate a pass signal if the signs of the signals at them are the same, and a fail signal if they are not.